

Diode EMCON 4 High Power Chip

FEATURES:

- 1200V EMCON 4 technology
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

• medium / high power modules



Applications:

medium / high power drives

Chip Type	V_R	I _F	Die Size	Package
IDC51D120T6H	1200V	100A	7.00 x 7.30 mm ²	sawn on foil

MECHANICAL PARAMETER:

Raster size	7.00 x 7.30				
Area total / active	51.10 / 39.99	mm^2			
Anode pad size	6.046 x 6.346				
Thickness	120	μm			
Wafer size	150	mm			
Flat position	180	deg			
Max. possible chips per wafer	277 pcs				
Passivation frontside	Photoimide				
Pad metall	3200 nm AlSiCu				
Backside metall	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500μm				
Reject ink dot size	Ø 0.65mm; max 1.2mm				
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



Maximum Ratings

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	V_{RRM}		1200	٧
Continuous forward current limited by T_{jmax}	/ _F		1)	A
Maximum repetitive forward current limited by T _{jmax}	I _{FRM}		200	
Maximum junction and storage temperature	$T_{\rm vj,max}$, $T_{\rm stg}$		-40+175	°C
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{F,max} = 2$	00A, $V_{R,max} = 1200V$, $T_{vj,op} \le 150^\circ$	PC , $P_{max} = \mathbf{tbd} \text{ kV}$	V

¹⁾ depending on thermal properties of assembly

Static Electrical Characteristics (tested on wafer), T_i =25 °C

Parameter	Symbol	Cond	Value			Unit	
i arameter	Joynnoor	Conditions		min.	Тур.	max.	
Reverse leakage current	I_{R}	V _R =1200V	<i>T_j</i> =25 °C			18	μΑ
Cathode-Anode breakdown Voltage	V _{Br}	I _R =0.25mA	<i>T_j</i> =25°C	1200			V
Forward voltage drop	V_{F}	$I_F = 100A$	<i>T_j</i> =25 °C	1.55	1.9	2.25	V

Dynamic Electrical Characteristics inductive load (not subject to production test - verified by design/characterization)

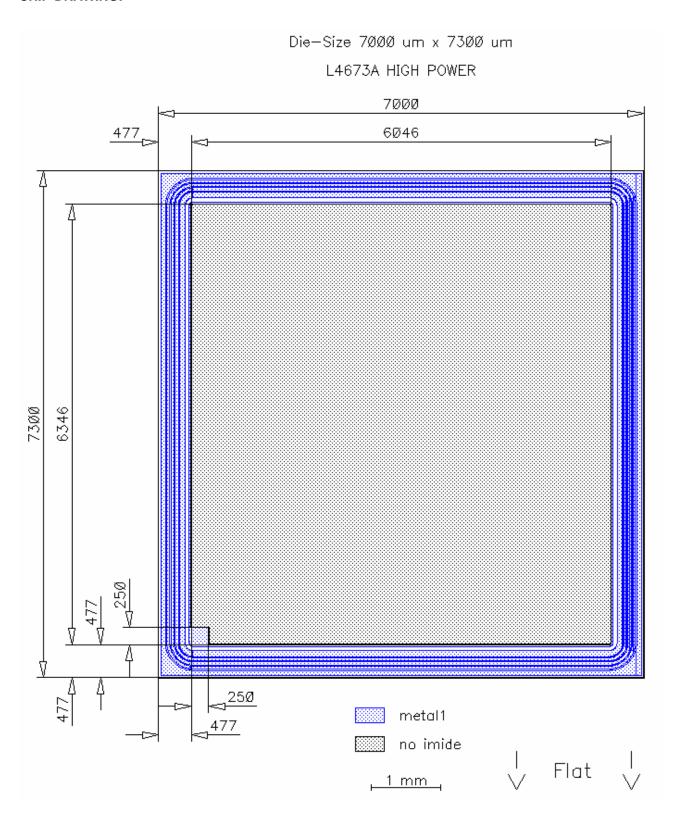
Parameter	Symbol	Conditions		Value 2)			Linit
rarameter	Symbol			min.	Тур.	max.	Unit
Peak reverse recovery current	I _{RM}	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		А
Reverse recovery charge	Q _r	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		μC
Reverse recovery energy	E _{rec}	$I_F = A$ di/dt = A/ms $V_R = V$ $V_{GE} = -15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		mJ

²⁾ values also influenced by parasitic L- and C- in measurement and package.

²⁾ not subject to production test - verified by design/characterisation



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:		
This chip data sheet refers to the device data sheet	tbd	
Description:		
AQL 0,65 for visual inspection according to failure	catalog	
Electrostatic Discharge Sensitive Device according	g to MIL-STD 883	
Test-Normen Villach/Prüffeld		

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